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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Quevedo-Lopez et al.

Art Unit: 2822

Serial No.: 10/726,987

Examiner: Thomas, T.

Filing Date: 12/03/2003

Docket No.: TI-36376

Customer No.: 23494

Conf. No.: 5051

Title: TOP SURFACE ROUGHNESS REDUCTION OF HIGH-k DIELECTRIC  
MATERIALS USING PLASMA BASED PROCESSES

ELECTION

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

MAILING CERTIFICATE UNDER 37 C.F.R. § 1.8(A)  
I hereby certify that the above correspondence is being deposited  
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1-27-05  
Date  
*Marianna Smith*  
Marianna Smith

Dear Sir:

With respect to the Restriction Requirement mailed on 01/04/2005, the Examiner has restricted the instant application to the invention of Group I (Claims 1-25), or Group II (Claims 26-31). In light of this, Applicants elect to pursue Group I, (Claims 1-25) without traverse.

The Examiner restricted the instant application to Species I – VII. Applicants elect to pursue Species VII with claims 5, 7, 9, and 10 readable thereon. Claims 1-3 and 11-25 are generic.

Respectfully submitted,

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